Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/668,881	GORRELL ET AL.	,	
Examiner	Art Unit		
Chris C. Chu	2815		

SEARCHED						
Class	Subclass	Date	Examiner			
257	E23.062, E23.069 & E23.07	9/30/2006	C.C.			
257	729 & 778	9/30/2006	C.C.			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; FPRS; and IBM_TDB;	9/30/2006	C.C.		
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